



# **General Description**

The AON3406 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. This device is suitable for use as a load switch or in PWM applications. The source leads are separated to allow a Kelvin connection to the source, which may be used to bypass the source inductance.

## **Features**

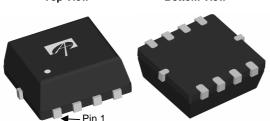
 $V_{DS}(V) = 30V$ 

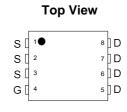
 $I_D = 10A (V_{GS} = 10V)$ 

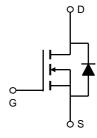
 $R_{DS(ON)} < 15 m\Omega \ (V_{GS} = 10 V)$ 

 $R_{DS(ON)}$  < 24m $\Omega$  (V<sub>GS</sub> = 4.5V)









Absolute Maximum Ratings T <sub>△</sub> =25°C unless otherwise noted
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Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		$V_{DS}$	30	V	
Gate-Source Voltage		$V_{GS}$	±20	V	
Continuous Drain	T <sub>A</sub> =25℃		10		
Current <sup>A</sup>	T <sub>A</sub> =70℃	I <sub>D</sub>	7.8	A	
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	30		
	T <sub>A</sub> =25℃	P <sub>D</sub>	3.0	W	
Power Dissipation A	T <sub>A</sub> =70℃	L D	1.9	] vv	
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	C	

Thermal Characteristics								
Parameter		Symbol	Тур	Max	Units			
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\theta JA}$	32	42	<b>℃</b> /W			
Maximum Junction-to-Ambient A	Steady-State	IΛθΊΑ	65	100	C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ heta JL}$	25	35	C\M			

#### Electrical Characteristics (T<sub>J</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Conditions		Тур	Max	Units			
STATIC PARAMETERS									
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D=250\mu A,\ V_{GS}=0V$	30			V			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V		0.003	1				
		T <sub>J</sub> =55℃			5	μΑ			
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ = ±20V			±100	nA			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ $I_{D}=250\mu A$	1.4	1.75	3	V			
$I_{D(ON)}$	On state drain current	$V_{GS}$ =4.5V, $V_{DS}$ =5V	30			Α			
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =10A		12	15	mΩ			
		T <sub>J</sub> =125℃		18	22	11122			
		$V_{GS}$ =4.5V, $I_D$ =9A		18	24	mΩ			
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =10A		30		S			
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V		0.73	1	V			
Is	Maximum Body-Diode Continuous Curre			4	Α				
DYNAMIC	PARAMETERS								
C <sub>iss</sub>	Input Capacitance			955	1200	pF			
C <sub>oss</sub>	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =15V, f=1MHz		145		pF			
$C_{rss}$	Reverse Transfer Capacitance			112		pF			
$R_g$	Gate resistance	$V_{GS}$ =0V, $V_{DS}$ =0V, f=1MHz		0.5	0.85	Ω			
SWITCHI	NG PARAMETERS								
Q <sub>g</sub> (10V)	Total Gate Charge			17	24	nC			
Q <sub>g</sub> (4.5V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =10A		9	12	nC			
$Q_{gs}$	Gate Source Charge	VGS-10V, VDS-10V, ID-10A		3.4		nC			
$Q_{gd}$	Gate Drain Charge			4.7		nC			
t <sub>D(on)</sub>	Turn-On DelayTime			5	6.5	ns			
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $R_{L}$ =1.5 $\Omega$ ,		6	7.5	ns			
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}$ =3 $\Omega$		19	25	ns			
t <sub>f</sub>	Turn-Off Fall Time	]		4.5	6	ns			
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =10A, dI/dt=100A/μs		19	21	ns			
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =10A, dI/dt=100A/μs		9	12	nC			

A: The value of R  $_{\theta JA}$  is measured with the device mounted on 1in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$ =25 $^{\circ}$ C. The value in any given application depends on the user's specific board design. The current rating is based on the t  $_{\circ}$  10s thermal resistance rating.

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B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300  $\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in <sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T A=25°C. The SOA curve provides a single pulse rating.

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

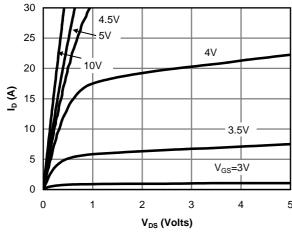


Fig 1: On-Region Characteristics

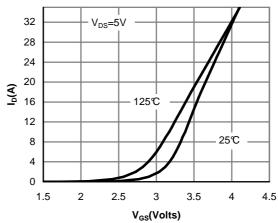


Figure 2: Transfer Characteristics

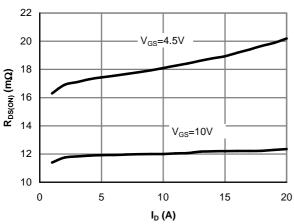


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

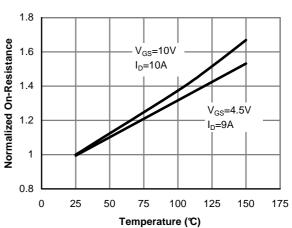


Figure 4: On-Resistance vs. Junction Temperature

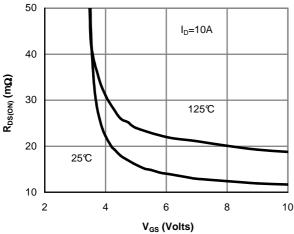


Figure 5: On-Resistance vs. Gate-Source Voltage

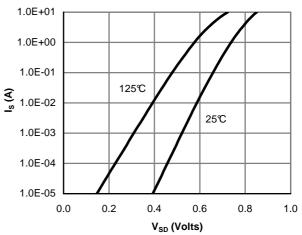


Figure 6: Body-Diode Characteristics

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

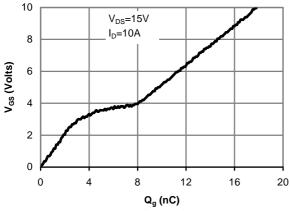


Figure 7: Gate-Charge Characteristics

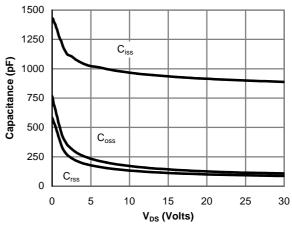


Figure 8: Capacitance Characteristics

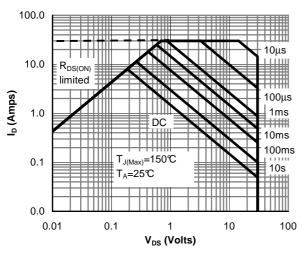


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

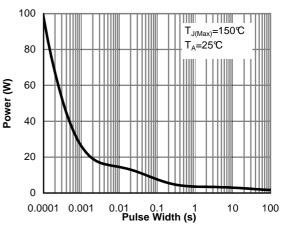


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

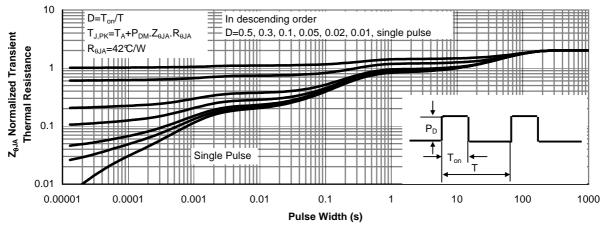


Figure 11: Normalized Maximum Transient Thermal Impedance